

<b>Notice of References Cited</b>	Application/Control No. 09/847,289		Applicant(s)/Patent Under Reexamination SHIN ET AL.	
	Examiner George A. Goudreau		Art Unit 1763	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,177,320	01-2001	Cho et al.	438/279
*	B	US-6,342,449	01-2002	Miyakawa, Yasuhiro	438/692
*	C	US-6,197,670	03-2001	Park, Byung-Jun	438/586
*	D	US-2002/0096772	07-2002	Ikemasu et al.	257/758
*	E	US-2002/0027259	03-2002	Ikemasu et al.	257/499
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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